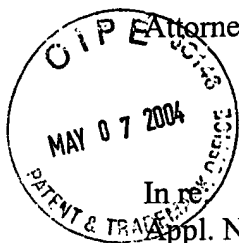


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JGW



Attorney's Docket No. 038190/273847

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re:	Fritzemeier, et al.	Confirmation No.:	Unknown
Appl. No.:	10/772,690	Group Art Unit:	Unknown
Filed:	February 5, 2004	Examiner:	Unknown
For:	CRYOMILLED ALUMINUM ALLOYS AND COMPONENTS EXTRUDED AND FORGED THEREFROM		

Commissioner for Patents
Washington, DC 20231

**SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT
CITATION UNDER 37 C.F.R. § 1.97**

Sir:

Attached is a list of documents on form PTO-1449 together with a copy of each identified document.

It is requested that the Examiner consider these documents and officially make them of record in accordance with the provisions of 37 C.F.R. § 1.97 and Section 609 of the MPEP. By submitting the listed documents, Applicant in no way makes any admission as to the prior art status of the listed documents, but is instead submitting the listed documents for the sake of full disclosure.

Respectfully submitted,

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CERTIFICATE OF MAILING

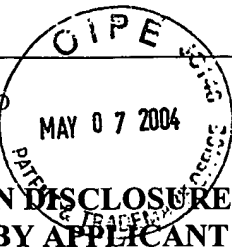
I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail in an envelope addressed to:
Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on May 4, 2004.

Tamara Stevens

Substitute for form 1449/PTO
(Revised 04/2003)

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(Use as many sheets as necessary)



Complete if Known

Application Number	10/772,690
Filing Date	February 5, 2004
First Named Inventor	Fritzemeier et al.
Group Art Unit	Unknown
Examiner Name	Unknown
Attorney Docket Number	038190/273847

Sheet 1 of 1

U. S. PATENT DOCUMENTS

Examiner Initials*	Cite No.	Document Number Number - Kind Code (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages of Relevant Figures Appear

FOREIGN PATENT DOCUMENTS

Examiner Initials	Cite No.	Foreign Patent Document Country Code - Number Kind Code (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	English Language Translation Attached

OTHER DOCUMENTS

Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	English Language Translation Attached
	11	LIAO, X.Z. ET AL., Deformation mechanisms at different grain sizes in a cryogenically ball - milled Al -Mg alloy, Ultrafine Grained Materials II (2002), 323-330, Photomicrographs, Diffraction Patters, 16 Ref. Minerals, Metals and Materials Society/Aime, Warrendale, PA; Conference: Ultrafine Grained Materials II	
	12	AIKIN, B..J.M. ET AL, Improvements in cryomill processing. Advanced Particulate Materials & Processes 1997 (1997), 287 - 294, Graphs, 6 Ref. Metal Powder Industries Federation, Princeton, NJ; Conference: 5th International Conference on Advanced Particulate Materials & Proce	
	13	LEE, Z. ET AL., Microstructural evolution of cryomilled nanocrystalline Al-Ti-Cu alloy, Ultrafine Grained Materials II (2002), 653-659, Diffraction Patters, Photomicrographs, Graphs, 10 Ref. Minerals, Metals and Materials Society/Aime, Warrendale, PA; Conference: Ultrafine Grained Materials II	
	14	CHOI, J.H. ET AL., Consolidation behavior of nanocrystalline Al -5at.%Ti alloys synthesized by cryogenic milling, Journal of Alloys and Compounds (9 Feb. 2001) 315, (1-2), 178-186, Diffraction Patterns, Photomicrographs, Graphs, 22 Ref. ISSN: 0925-8388	

Examiner
Signature

Date
Considered

*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.